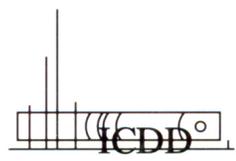
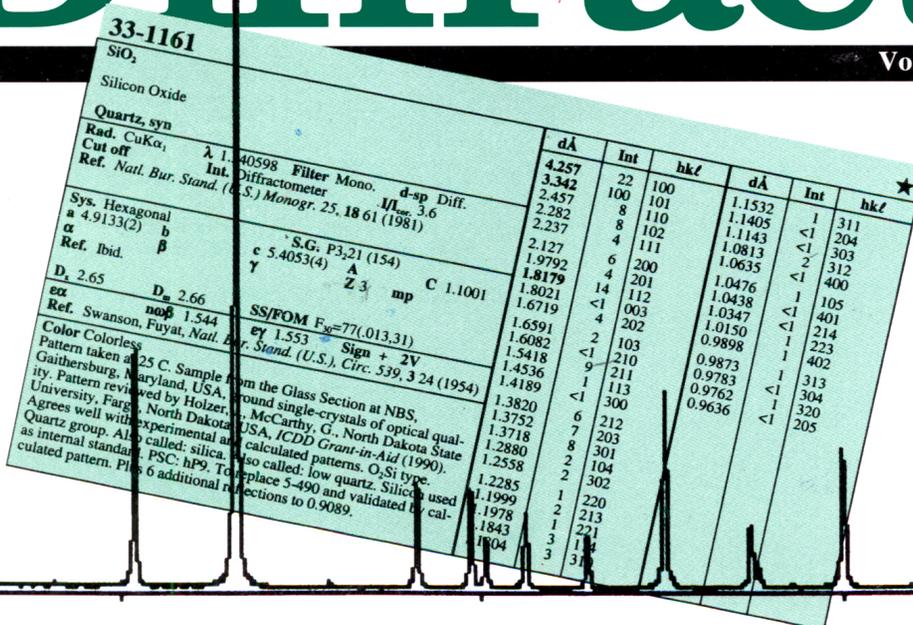


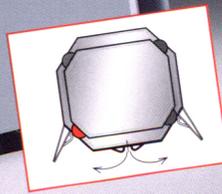
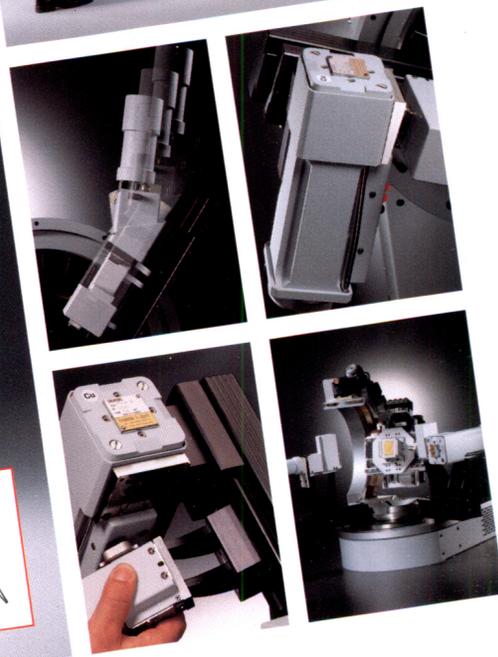
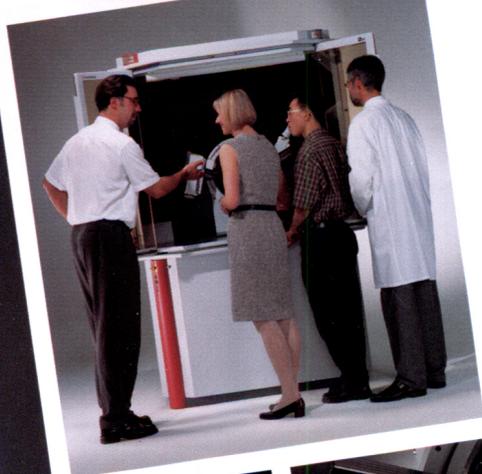
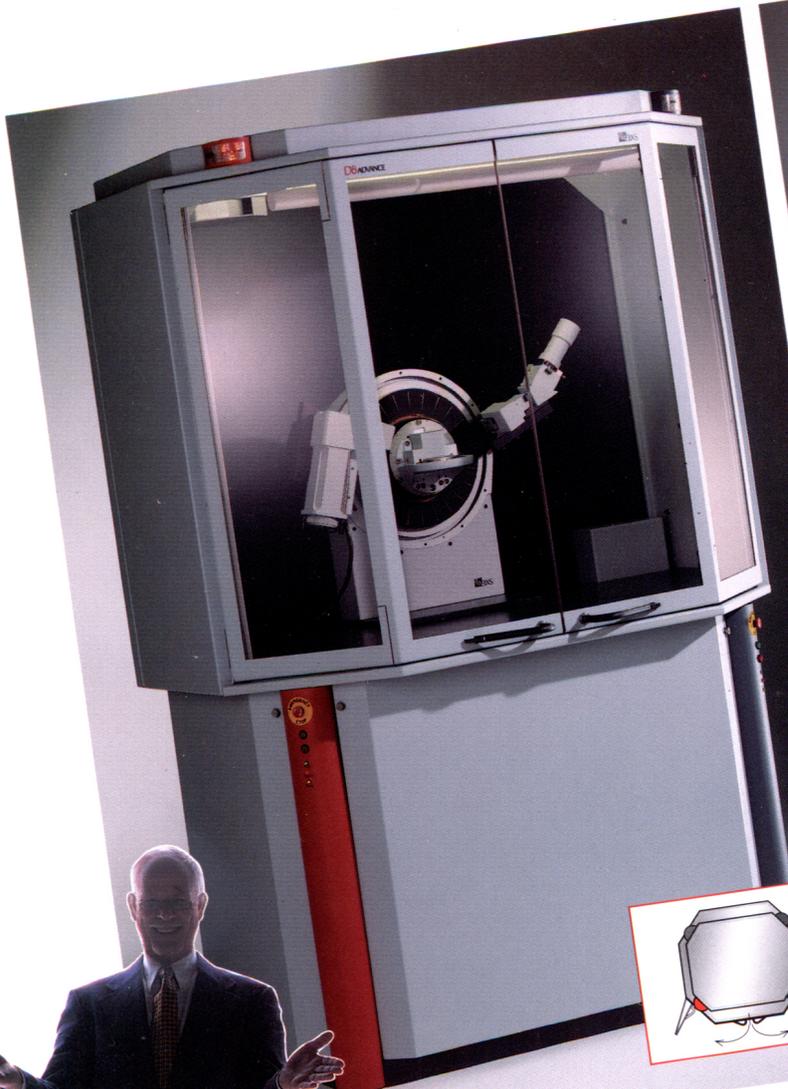
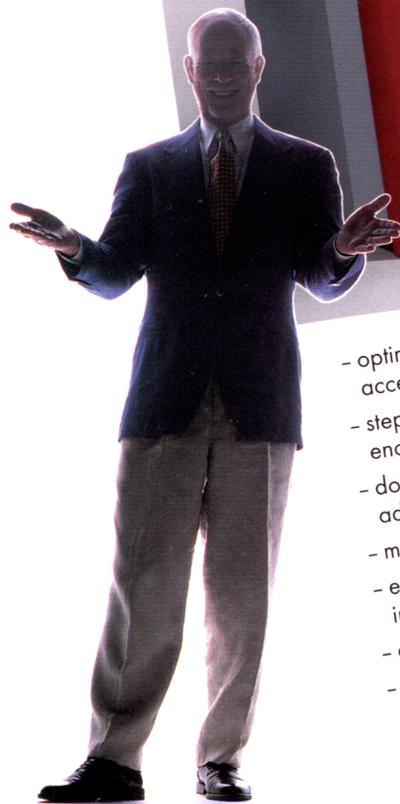


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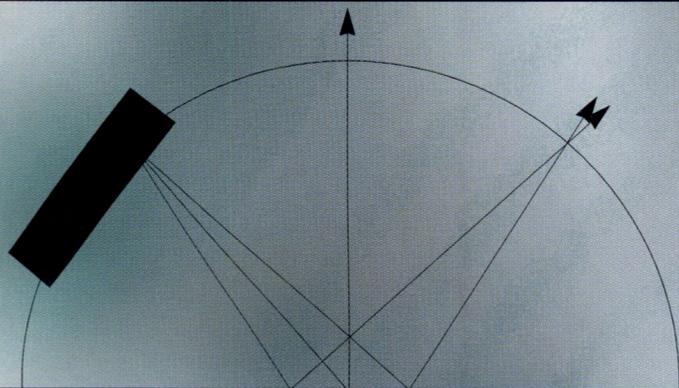
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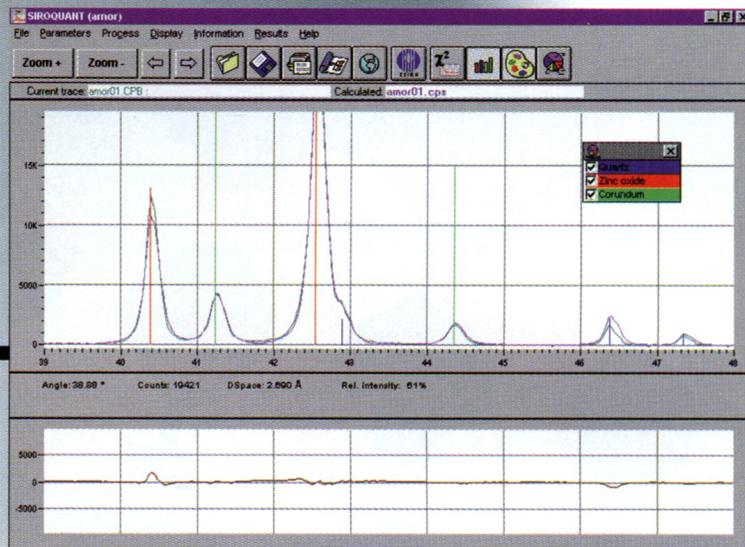
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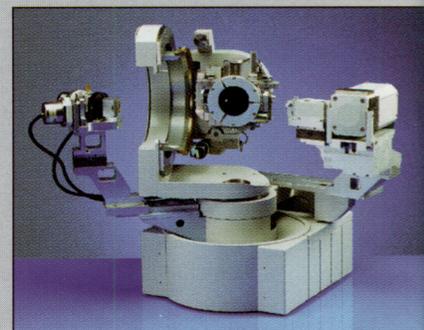
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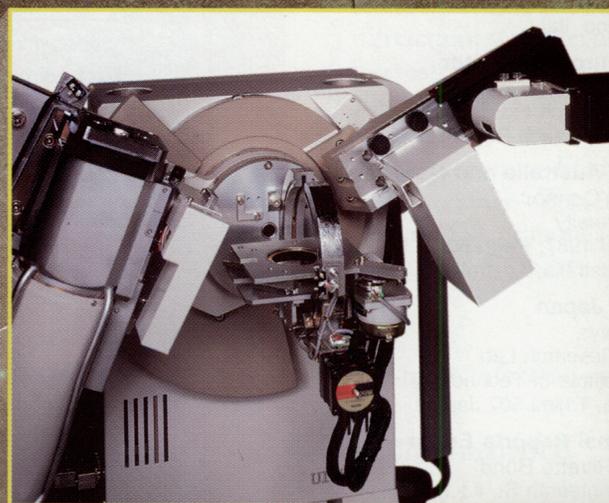
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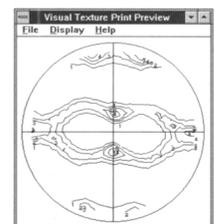
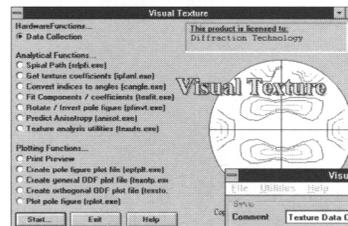
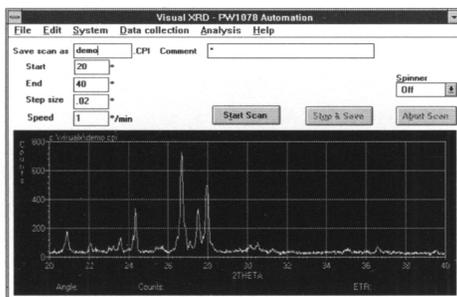


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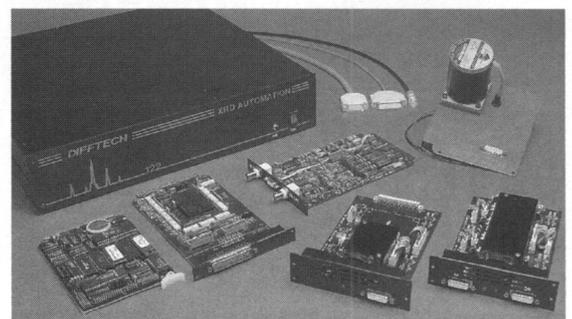
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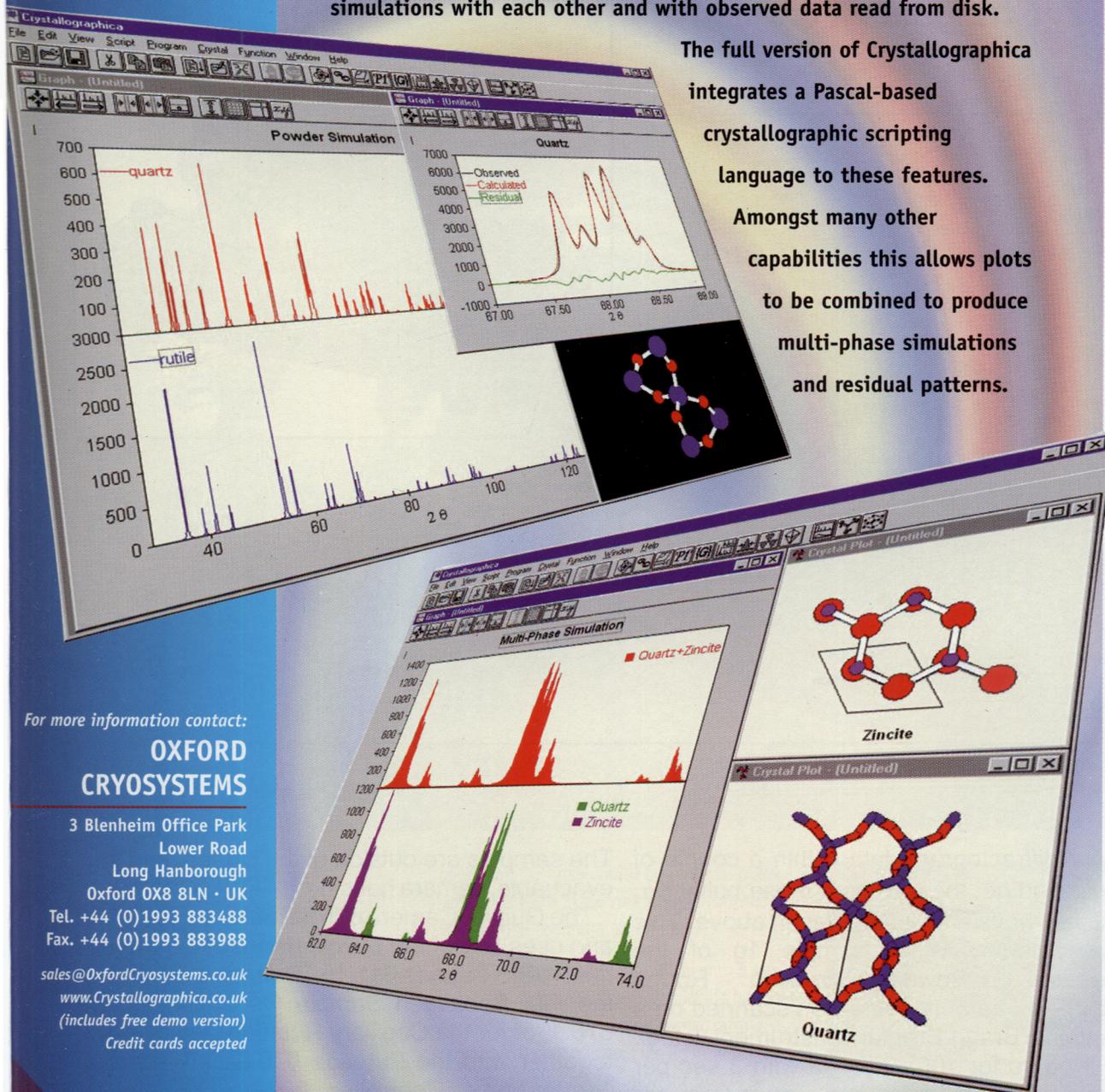
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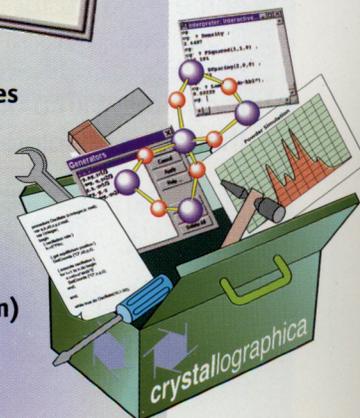
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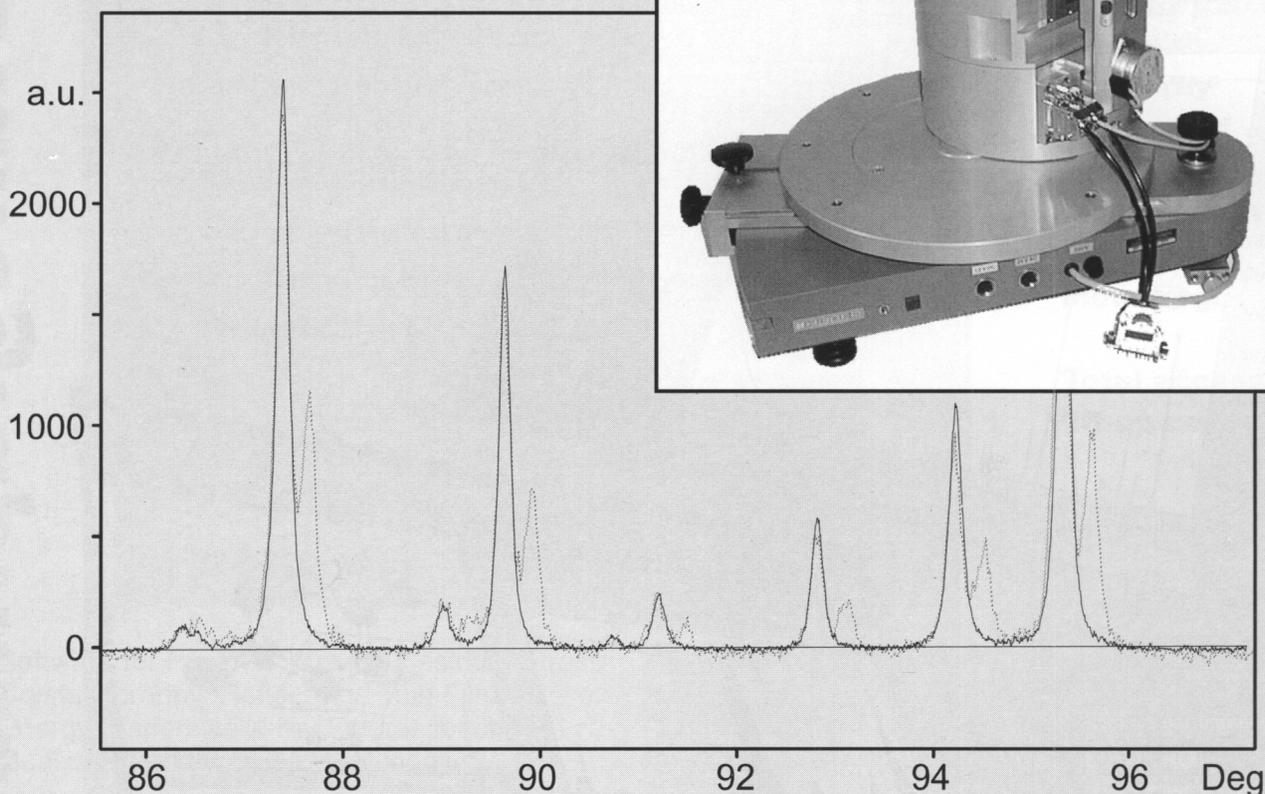
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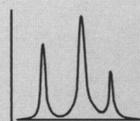
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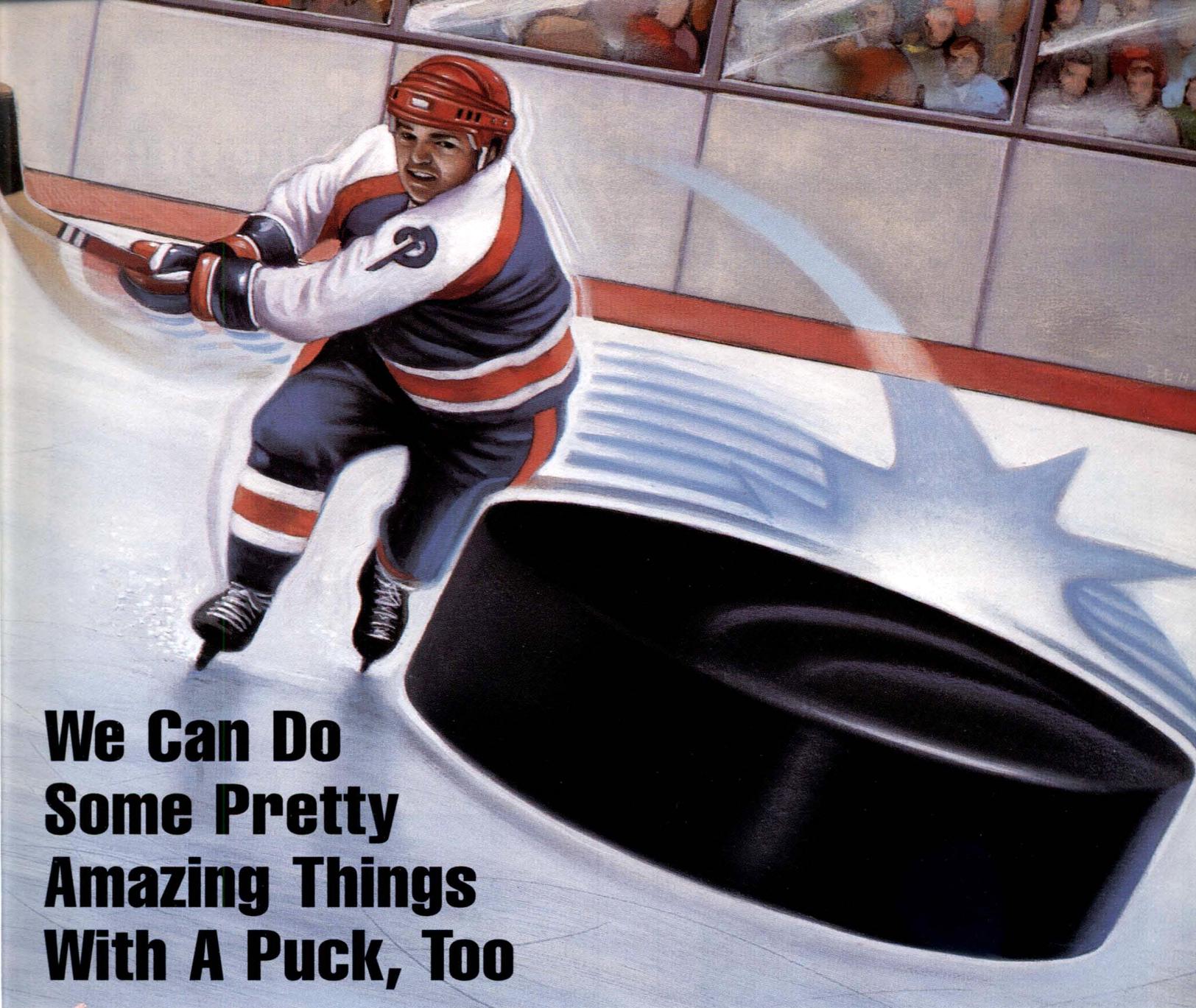
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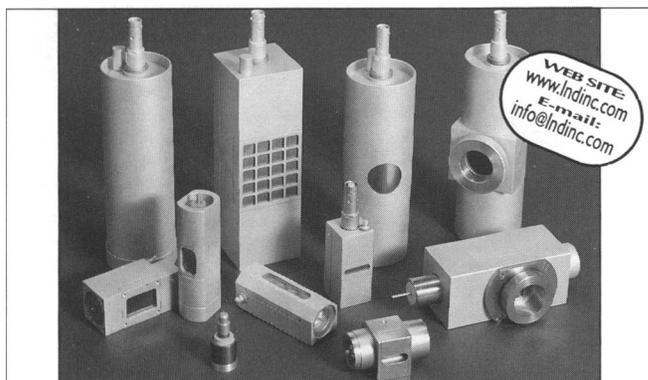
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RE: X-RAY DIFFRACTION

Periodic Maintenance

Service contracts for parts and labor on X-ray
Periodic Alignment of Goniometers.
Installation and training

X-RAY Component Repair:

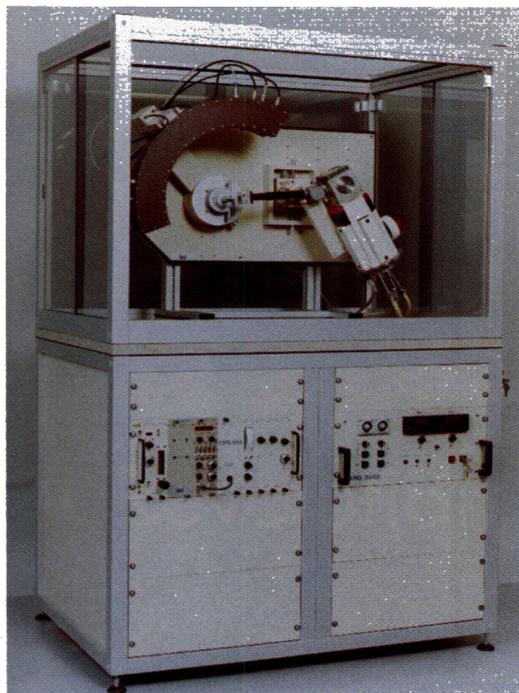
Rebuild of Goniometers (includes Imron pair
Scintillation Detector X-Tal replacement
High Voltage Tank repairs. vacuum pumped

UPGRADES and MODIFICATIONS

Equipped Machine shop for special designed
PC Automation. for Data acquisition and An
Diffraction Scans. DOS & Mac Systems ava
Safety Upgrades. new style auto shutters. bea
and slit assemblies.

Sample Changers. Sample Rotation. Monoch
X-ray Tubes. etc.

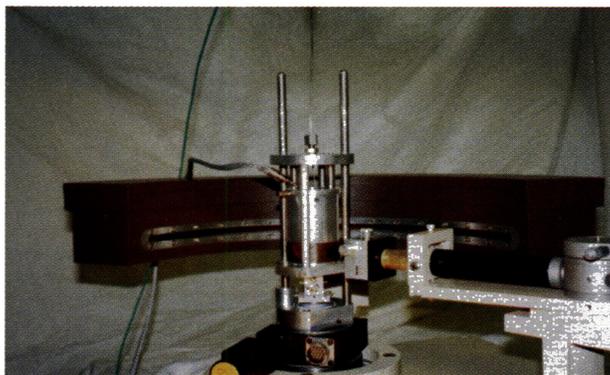
XRD XRF EDS WDS



MPD Multi-Purpose X-ray
Diffractometer

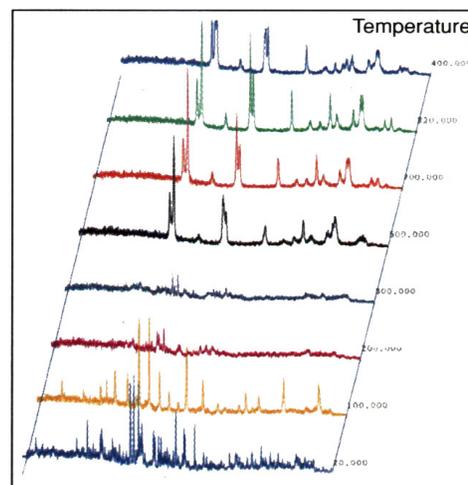
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- Microcrystalline polymorph identification
- Newly synthesized materials identification
- Thin films
- Electrochemistry
- Kinetic transformations of ceramics
- In-Situ Measurements



3D Plot 2θ vs. Temperature

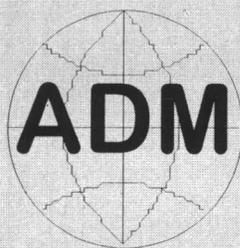
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Grant-in-Aid

from the International Centre for Diffraction Data

The International Centre for Diffraction Data (ICDD) is interested in high quality experimental powder diffraction patterns to add to its internationally renowned database, the Powder Diffraction File™ (PDF®). If you had additional financial support, could you produce some high quality X-ray powder diffraction patterns? If the answer is yes, consider applying for an ICDD Grant-in-Aid.

A grant can be used most effectively as supplement to existing funded projects involving the preparation and characterization of new materials, using powder XRD. Grant-in-Aid proposals will be considered, on a worldwide competitive basis, from any qualified investigator, who can demonstrate expertise in the preparation of high quality powder diffraction patterns.

Currently, there are two grant cycles. Proposal deadlines are

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Cycle II	31 July

The duration of a grant is 12 months, which can be considered for renewal, again on a competitive basis, if the first grant is completed successfully. Recipients are required to submit biannual progress reports and must reapply every year if they wish to be considered for renewal.

For more information, please review the guidelines found at ICDD's web site: <http://www.icdd.com>. An application with guidelines may be obtained by contacting the ICDD's Data Acquisition Manager at the address below.

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International Centre for Diffraction Data
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Newtown Square, PA 19073-3273 U.S.A.

Telephone: (610) 325-9814
Fax: (610) 325-9823
E-mail: Mauchline@icdd.com

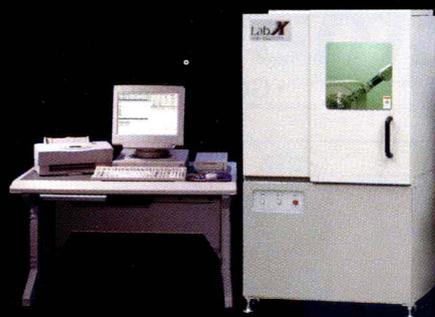
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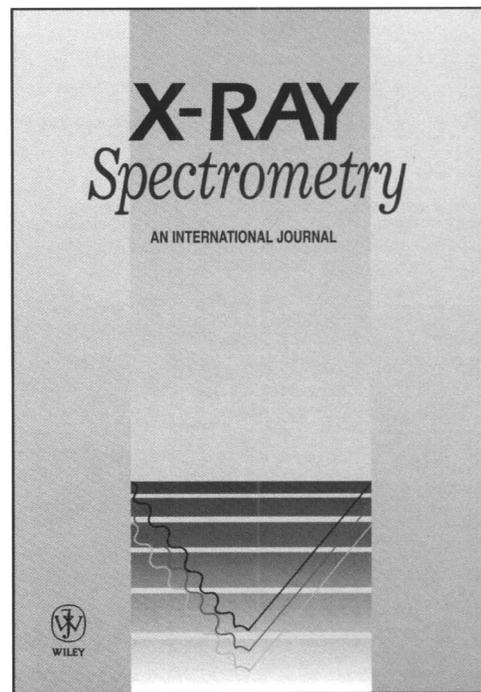
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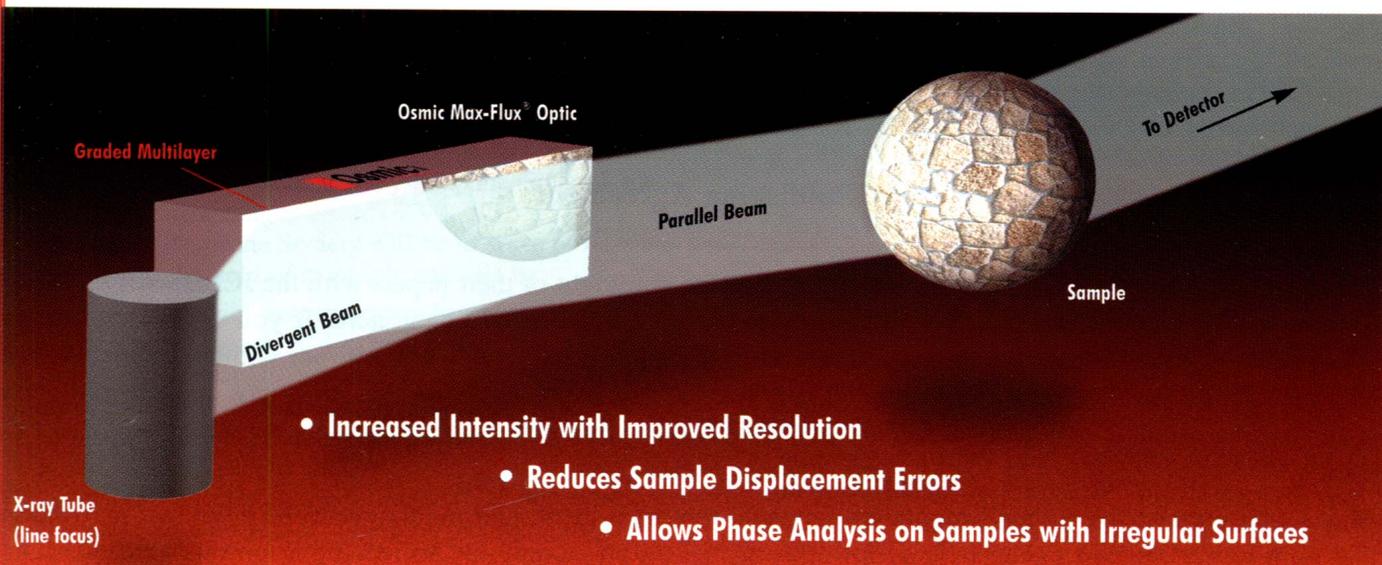
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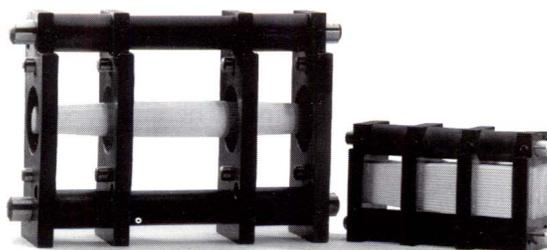


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